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	Application Number	Notivet Assigned (4 Q)	
LOSURE	Filing Date	Concurrently Herewith	
PLICANT	First Named Inventor	Ingrid Bach	
	Art Unit	N/A	
essary)	Examiner Name	Not Yet Assigned	
1	Attorney Docket Number	09931-00051-US	
	CLOSURE PLICANT cessary)	Application Number LOSURE Filing Date PLICANT First Named Inventor Art Unit Examiner Name	

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No.1	Document Number Number-Kind Code ² (#known)	Publication Date MM-DD-YYYY	Name of Patentea or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
/JK/	AA*	4,539,507	09-03-1985	Van Slyke et al.	
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Examiner Initials*	Cite No.1	Foreign Patent Document Country Code ³ -Number ⁴ - Kind Code ⁶ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ^e
/JK/	ВА	WO-02/060910	08-08-2002	Covion Organic Semiconductors GmbH		
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/JK/	ВС	JP-2004-168756	06-17-2004	Dokuritsu Gyosei Hojin Sangyo Gijutsu So		See Abstract
/JK/	BD	JP-2004-168758	06-17-2004	Dokuritsu Gyosei Hojin Sangyo Gijutsu So		See Abstract
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/JK/	BF	DE-103 14 102	10-14-2004	Covion Organic Semiconductors GmbH		See Abstract

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	NON PATENT LITERATURE DOCUMENTS		
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/JK/	CA	Konno, Hideo et al., "Selective One-Pot Synthesis of Facial Tris-Ortho-Metalated Iridium (III) Complexes Using Microwave Irradiation", Chemistry Letters 32(3)(2003), pp. 252. (XP- 002296233)	

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